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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2811  
Examiner: To Be Assigned

In Re PATENT APPLICATION of:

Applicant(s): Akio NAKAMURA

Serial No.: 10/712,090

Filed: November 14, 2003

For: SEMICONDUCTOR DEVICE AND  
ITS MANUFACTURING METHOD

Atty Ref.: SAT 198

**INFORMATION  
DISCLOSURE  
STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

This is an information disclosure statement submitted in compliance with the timing requirements of 37 C.F.R. §1.97(b)(3), i.e., prior to a first Office Action on the merits.

Attached are copies of two Japanese patent publications with their English-language abstracts, from which any relevance of the publications may be gleaned. The publications are listed on the attached Form PTO-1449. The references were first cited on September 14, 2004, by the Japanese Patent Office in an Office Action issued in connection with the counterpart Japanese patent application.

Since this Information Disclosure Statement is being filed before a first Office Action, no certification or fee is required, and the requirements of 37 C.F.R. §§1.97 and 1.98 are deemed to be fully met as to all documents listed. Consideration of the listed documents respectfully is requested.

Should any fee be required, the Commissioner is hereby authorized to charge such fees to our Deposit Account No. 18-0002.

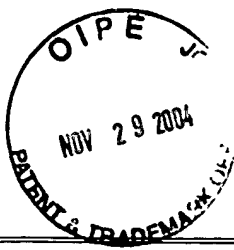
Respectfully submitted,

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November 29, 2004  
Date

RHB:vm

FILE ENCLOSED: \$  
Please charge any further  
fee to our Deposit Account  
No. 18-0002



<b>FORM PTO-1449</b> <b>INFORMATION DISCLOSURE STATEMENT</b>				Atty. Docket  SAT 198		Application No.  10/712,090	
				Applicant Akio NAKAMURA			
				Filing Date November 14, 2003		Group 2811	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
<b>FOREIGN PATENT DOCUMENTS</b>							
		Document Number	Date	Country	Class	Sub-Class	Translation
	AI	2001-292026	10/19/01	JAPAN			Abstract
	AJ	2002-043468	02/08/02	JAPAN			Abstract
	AK						
	AL						
	AM						
	AN						
<b>OTHER (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AO						
Examiner					Date Considered		
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							